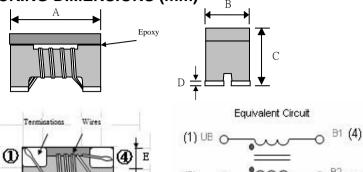
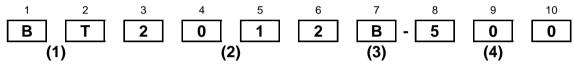
# Version: 1.0 SPECIFICATION ROHS COMPLIANT ITEM P/N BT2012B-500 TEST INSTRUMENT Network Analyzer PRODUCT Chip Balun Transformer Freq. Range(MHz) 40~860





| BT2012B | Dimensions    |
|---------|---------------|
| Α       | $2.0 \pm 0.2$ |
| В       | $1.2 \pm 0.2$ |
| С       | $1.2 \pm 0.2$ |
| D       | $0.2 \pm 0.1$ |
| Е       | 0.40 Typ      |
| F       | 0.45 Typ      |

#### **EXPLANATION OF PART NUMBERS**



- (1) Product name
  - Chip Balun Transformer
- (2) Dimensions (L X W) (mm) 2.0 X 1.2
- (3) Shielding Type for 1.0 GHz
- (4) Impedance 750:75Ω

Recommended Soldering Conditions (Please use this product by reflow soldering)

| 0.9 | 0.8 |  |
|-----|-----|--|

#### **ELECTRICAL CHARACTERISTICS**

| P/N         | Freq.<br>Range<br>(MHz) | UB/B<br>Impedance<br>(ohm) | Insertion<br>Loss<br>(dB) | CMRR<br>(dB) | Rated<br>Voltage<br>(V) | Withstand<br>Voltage<br>(DC) | Insulation Resistance Min. ( $M\Omega$ ) |
|-------------|-------------------------|----------------------------|---------------------------|--------------|-------------------------|------------------------------|--|
| BT2012B-500 | 40~860                  | 50/50                      | 2.5 max                   | 20 min       | 20                      | 125V                         | 10                                       |

- Operating and storage temperature range (individual chip without packing): -40°C ~ +85°C.

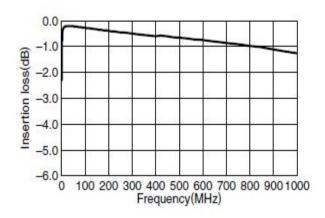
Page: 1



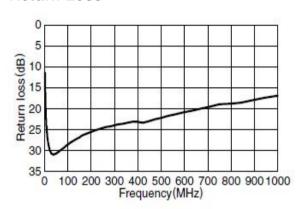
## **HUNGTRON TECHNOLOGY CO.,LTD**

| Version: 1.0 | CHARACTER              | RoHS<br>COMPLIANT |                  |
|--------------|------------------------|-------------------|------------------|
| ITEM P/N     | BT2012B-500            | TEST INSTRUMENT   | Network Analyzer |
| PRODUCT      | Chip Balun Transformer | Freq. Range(MHz)  | 40~860           |

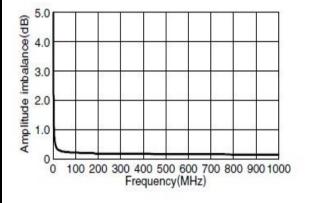
#### **Insertion Loss**



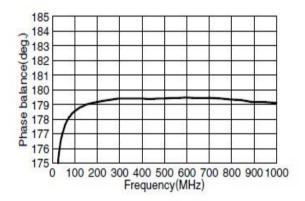
#### **Return Loss**



#### **Amplitude Imbalance**



#### **Phase Balance**





# Version: 1.0 CHARACTERISTICS ROHS COMPLIANT ITEM P/N BT2012B-500 TEST INSTRUMENT Network Analyzer PRODUCT Chip Balun Transformer Freq. Range(MHz) 40~860

#### **Electrical Test**

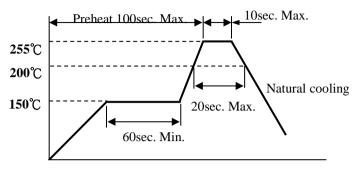
| TEST                     | Requirement                                     | Method Used   |
|--------------------------|---|---|
| Insertion<br>Loss        | Refer to<br>Page1 ELECTRICAL<br>CHARACTERISTICS | Insertion Loss is measured with Network Analyzer  Port1  Port2  Port2   |
| CMRR                     | Refer to<br>Page2 ELECTRICAL<br>CHARACTERISTICS | Common Mode Rejection Ratio (CMRR) is a function of both amplitude imbalance and phase imbalance. If a differential VNA is not available, CMRR can be computed based on single ended measurement.  CMRR[dB] = 20log10(Sds21/Scs21) = 20log10{(S21+S31)/(S21-S31)}  Where,  Sds21 is S-parameter of single mode stimulus - Differential mode response Scs21 is S-parameter of single mode stimulus - Common mode response It is assumed that the single-ended S-parameters are obtained with proper matched-load termination at each port. |
| Withstand<br>Voltage     | Refer to<br>Page3 ELECTRICAL<br>CHARACTERISTICS | Apply DC Voltage between Terminal 1 and Terminal 2 for 5 seconds. The DC Voltage is 2.5 times of the rated voltage. No damage shall be observed after the testing.  Terminal 1  Terminal 2  Terminal 2  |
| Insulation<br>Resistance | Refer to<br>Page4 ELECTRICAL<br>CHARACTERISTICS | Test equipment: High resistance meter HP4339.  Apply rated voltage, then measure resistance between Terminal 1 and Terminal2.  Terminal 1   Terminal 2   Terminal 2   |



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| Version: 1.0 | 1.0 RELIABILITY        |                  |                  |  |  |
|--------------|------------------------|------------------|------------------|--|--|
| ITEM P/N     | BT2012B-500            | TEST INSTRUMENT  | Network Analyzer |  |  |
| PRODUCT      | Chip Balun Transformer | Freq. Range(MHz) | 40~860           |  |  |

#### **RECOMMENDED SOLDERING TEMP. GRAPH**



#### **MECHANICAL RELIABILITY**

| TEST              | Specification & R                        | equirement           | Method Used                                    |  |
|-------------------|--|----------------------|--|--|
|                   | The surface of terminal/pin tested shall |                      | Solder heat proof:                             |  |
| Solderability     | be covered with new solder by 90%        |                      | Preheating: 150 ±10℃ 60 seconds                |  |
|                   |  |                      | Soldering: 245 ±5℃ for 4 ±1 sec                |  |
|                   | Components should have not evidence of   |                      | Preheating:150°C 60secs                        |  |
| Solder Heat       | electrical and mechannical damage        |                      | Solder temperature: 260±5°ℂ                    |  |
| Resistance        | Impedance:within ±15% of initial value   |                      | Flux:rosin                                     |  |
|                   |  | Dip time:10±0.5 secs |  |  |
|                   | Series No.                               | F (Kg)               | Solder a chip to test substrate and then       |  |
|                   | BT2012A-750                              | 0.5                  | laterally apply a force in the arrow direction |  |
| Terminal strength |  |                      | Test Board                                     |  |

## ENDURANCE RELIABILITY

| TEST                  | Specification & Requirement           | Method Used                                    |
|-----------------------|---------------------------------------|--|
|                       | Impedance change within ± 15% Without | -65°C, (30 mins) -> room temp. (2 mins) ->     |
| Thermal Shock         | mechanical damage                     | <b>125</b> ℃, (30 mins) -> room temp. (2 mins) |
|                       |                                       | 50 cycles                                      |
| Humidity              | Impedance change within ± 15% Without | Apply IDC current @ 60°C ambient               |
| Resistance            | mechanical damage                     | Humidity: 90%                                  |
| Resistance            |                                       | Duration: 168 hrs                              |
| Low Temp.             | Impedance change within ± 15% Without | Storing Temp.                                  |
| Storing               | mechanical damage                     | -40 ±2 ℃ for total 168 +5/-0 hours             |
| Lliab Tanan           | Impedance change within ± 15% Without | Storing Temp.                                  |
| High Temp.<br>Storing | mechanical damage                     | 125 ±2 °C for total 168 +5/-0 hours            |

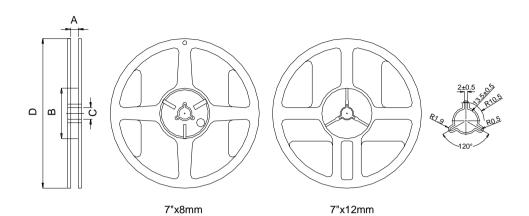
Page: 4



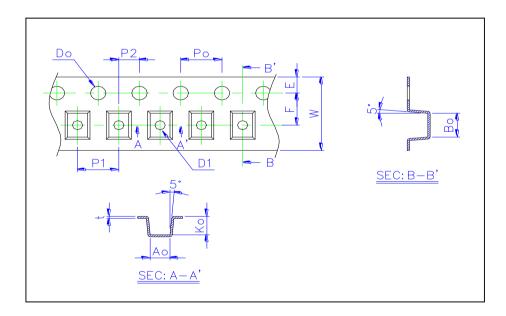
## **HUNGTRON TECHNOLOGY CO.,LTD**

| Version: 1.0 PACKING FOR SMD ROHS |                        |                  |                  |  |  |
|-----------------------------------|------------------------|------------------|------------------|--|--|
| ITEM P/N                          | BT2012B-500            | TEST INSTRUMENT  | Network Analyzer |  |  |
| PRODUCT                           | Chip Balun Transformer | Freq. Range(MHz) | 40~860           |  |  |

### Reel Dimension & Tape Dimension



| Type   | A(mm)   | B(mm) | C(mm)    | D(mm) |
|--------|---------|-------|----------|-------|
| 7"x8mm | 9.0±0.5 | 60±2  | 13.5±0.5 | 178±2 |



| Size | Ao(mm)    | Bo(mm)    | Ko(mm)    | W(mm)     | E(mm)     | F(mm)     | Po(mm)   | P1(mm)   | Do(mm)  |
|------|-----------|-----------|-----------|-----------|-----------|-----------|----------|----------|---------|
| 2012 | 2.35±0.10 | 1.50±0.10 | 1.45±0.10 | 8.00±0.20 | 1.75±0.10 | 3.50±0.05 | 4.0±0.05 | 4.0±0.10 | 1.0±0.1 |

### **Packaging Quantity**

| Chip Size | 2012 |
|-----------|------|
| 8mm/ Reel | 2000 |



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